

4 A Through-Silicon Metrology Target for Solid Immersion Lenses, Part II: Other Applications

William Lo and Howard Marks

A technique for converting a frontside metrology target for backside use was presented in Part I of this article in the February issue. Part II describes other applications of the metrology chip as well as its limitations.

10 Finding the “When” and Improving the “Where” with Picosecond Time-Resolved LADA

Dan Bodoh and Kent Erington

Picosecond time-resolved LADA can measure the time of a failing transition relative to the start of the test loop. It enables faster resolution of issues and is a useful tool for root-cause identification.

18 Capacitor Failure and Helicopter Accident

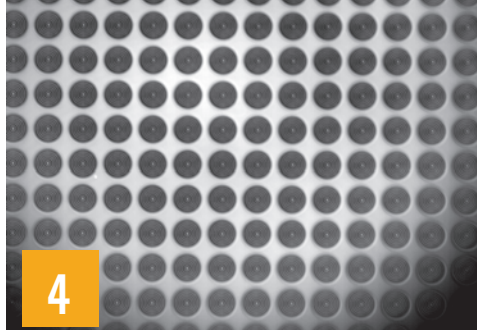
Frédéric Walbrou

A safety investigation of a helicopter accident used chip-level recovery procedures to retrieve recorded flight data that determined the cause of the crash.

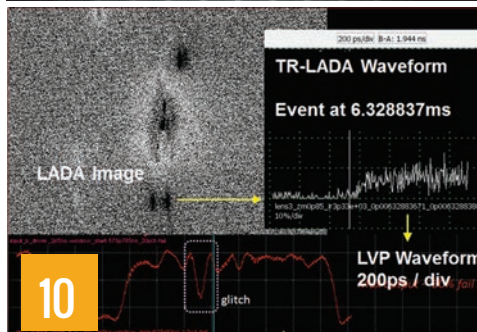
28 ANADEF 2014 Workshop Report

Alain Wislez

Read a review of the biennial ANADEF Workshop, which includes prize-winning images from its photo contest.



4



10



18

ABOUT THE COVER

FIB cross-sectional image showing the point contact of a metal-3-to-metal-1 short circuit. This elusive failure mechanism was caused by a boundary defect along the metal 2 bus, allowing the metal 3 barrier metal to spike down to metal 1. Photo by Kristopher D. Staller, Texas Instruments, First Place Winner in Black and White Images, 2014 EDFAS Photo Contest.

Author Guidelines

Author guidelines and a sample article are available at edfas.org. Potential authors should consult the guidelines for useful information prior to manuscript preparation.

DEPARTMENTS

48 ADVERTISERS' INDEX

34 DIRECTORY OF FA PROVIDERS *Rose Ring*

2 GUEST EDITORIAL *Jeremy D. Russell*

40 LITERATURE REVIEW *Mike Bruce*

32 MASTER FA TECHNIQUE *Doug Hamilton and Phoumra Tan*

44 PRODUCT NEWS *Larry Wagner*

38 TRAINING CALENDAR *Rose Ring*

42 UNIVERSITY HIGHLIGHT *Christian Boit*

30 2015 PHOTO CONTEST

31 2015 VIDEO CONTEST